



Sensor devices Thermal sensors







Outline



- 7 Thermal sensors
 - Introduction
 - •Heat transfer
 - •Thermal structures
 - •Thermal-sensing elements
 - •Thermal and Temperature sensors



Introduction



- Physical quantitaties is converted into heat
- The heat is converted into electrical quantities
- The process is done into three steps
 - Electromagnetic radiation is transduced into a heat flow
 - The heat flow is converted into a temperature difference
 - The temperature difference is transduced into a electric signal using a temperature (difference) sensor





- Heat
 - Gas and Liquid "average velocity of the molecules"
 - Solids "Phonons, vibrations of atoms in lattice and transportations of heat by free electrons"
- Specific heat and thermal capacitance
 - Heat required to increase the temperature with 1 K at constant pressure

$$c_p = \left(\frac{dH}{dT}\right)_p$$







Conduction

Conductivity
Heat will flow from hotter to colder region

Convection

Heat transfer to flowing fluids (Liquid or gas)
Laminar flow
Turbulent flow







Radiation

- -Black-body Radiation
 - •A body which absorb all of the radiation " absorptivity=1" is called a black body
 - •A black-body with absorptivity=1 also have an emissivity=1

•Stefan-Boltzmann law

$$P''_{\rm rad}(T) = \epsilon \sigma T^4$$

 $\sigma = 56.7 \times 10^{-9} \text{ W/m}^2 \text{-} \text{K}^4$.







Т

Heat transfer by infrared radiation
 Two parallel plates

$$G''_{\rm rad} = 4 \epsilon \sigma T^3 = \epsilon \times 6 \text{ W/K-m}^2.$$

•Silicon is almost transparent above 1.1 um. At room temperature the radiation have its maximum at 10 um wavelength and the absorptivity, emissivity is as low as 0.1-0.3









•Purpose

-Reduce "self heating"

-Reduce "heat leakage"

In case of temperature difference like sensor structure, make R_{th} large $R_{th}=\Delta T/P$

Often solved by using thin membranes

•The membrane can be of type











TABLE 1 Electrical Equivalents of Thermal P	Parameters	
Thermal Parameter	Electrical Parameter	
Temperature: T (K)	Voltage: V (V)	
Heat flow, Power: P (W)	Current: I (A)	
Heat: $O(J = W s)$	Charge: Q (C = A-s)	
Resistance: R (K/W)	Resistance: $R (\Omega = V/A)$	
Conductance: $G(W/K)$	Conductance: $G(S = \Omega^{-1})$	
Capacity: $C (J/K)$	Capacitance: C (F = A-s/V)	
Thermal resistivity: ρ_{th} (K-m/W)	Electrical resistivity: ρ_{el} (Ω -m)	
Thermal conductivity: κ (W/K-m)	Electrical conductivity: σ (S/m)	
Specific heat: c_p (J/kg-K)	Permittivity: ε (F/m)	





One dimensional heat flow



Fig. 5 One-dimensional heat flow along the axis of rods, wires, rectangular plates and tubes. The symbol L denotes the linear dimension in the direction of the heat flow. (After Ref. 1)

Thermal resistance 1 dimension *K*= thermal conductivity

Thermal resistance of object in fig 5a

$$R_{\rm th} = \frac{L}{\kappa A}$$

$$R_{\rm th} = \frac{L}{W} \frac{1}{\kappa D}.$$









MID SWEDEN UNIVERSITY



Cantilever beam and bridges In case of heat convection and infrared radiation











- Resistors
 - Bridge coupled mono or poly silicon resistors
 - Platinum resistors Pt100, 100ohm at 0°C, 0.38%/K
- Thermopile
- Acoustic sensing elements









Seebeck Coefficients

Material	273 K		300 K
p-type mono silicon (Si)			300 to 1000
Antimony (Sb)		43ª	
Chrome (Cr)	18.8		17.3
Gold (Au)	1.79		1.94
Copper (Cu)	1.70		1.83
Aluminum (Al)			-1.7
Platinum (Pt)	-4.45		-5.28
Nickel (Ni)	-18.0		
Bismuth (Bi)		-79^{a}	
<i>n</i> -type polysilicon (Si)			-200 to -500





Seebeck Coefficients, dependencies of temperature and doping in p-type silicon









- Acoustic wave sensors
- feedback loop, oscillators
- sensitivity ~2.8kHz/°C







Thermopile, SU8 with Ni and Ti as thermopile element























Figure 5. Top view image of IR sensitive resistances $(R_2 \text{ and } R_4)$ on fabricated bolometer.



Figure 6. Measured detector response from a 1.56 µm laser with a power of 4.5 mW.







Exercises



Processing part (chapter 2)

- **3.1** How long does it take to grow 100 nm of oxide in wet oxygen at 1000 °C (assume 100 silicon)? In dry oxygen? Which process would be preferred?
- 3.2 A 1.2-μm silicon dioxide film is grown on a <100> silicon wafer in wet oxygen at 1100 °C. How long does it take to grow the first 0.4 μm? The second 0.4μm? The final 0.4 μm?
- **4.1** A phosphorus diffusion has a surface concentration of 5×10^{18} /cm³, and the background concentration of the *p*-type wafer is 1×10^{15} /cm³. The *Dt* product for the diffusion is 10^{-8} cm².
 - (a) Find the junction depth for a Gaussian distribution.
 - (b) Find the junction depth for an erfc profile.
 - (c) What is the sheet resistance of the two diffusions?
 - (d) Draw a graph of the two profiles.

3.1 9 min, 2.3h 4:1 5.8 um, 5.3 um, 470hm/Square, 60 ohm/square



Exercise



- 6. Thermal Model of Floating-Membrane Sensor. A floating-membrane sensor has a suspension beam 2 mm in length, 200 μ m in width and 5 μ m in thickness ($\kappa_{si} = 150 \text{ W/K-m}$). At its end a floating membrane is suspended with an area of 2 mm², between heat sinks at 0.5 mm distance under and above the membrane. The sensor is encapsulated in argon ($\kappa_{Ar} = 18 \text{ mW/K-m}$).
 - a) What is the beam's thermal resistance compared to that of the floating membrane?
 - b) How do the thermal time constants of the beam and the overall system (using a simple model) compare? Note, that the specific heat of silicon is $c_p = 1.6 \text{ MJ/m}^3\text{-K}$.

